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## HEXAGONAL SENSOR WITH IMBEDDED ANALOG IMAGE PROCESSING FOR PATTERN RECOGNITION

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### ABSTRACT

This paper presents multi-module focal plane processing sensor architecture which provides high resolution (up to 512 x 512 pixels) multiscale real time analog edge extraction for robot vision. The hexagonal CMOS sensor uses a multiport addressing architecture of the pixel array in order to apply external multiscale analog spatial convolution followed by edge detection. The sensor architecture and its peripheral analog filtering modules are described and relevant results obtained from an actual 256x256 prototype are presented. This analog satellite processing approach may be extended to various types of computational sensors including 3D range finder, motion sensors or tactile perception devices. This multi-module approach allows the implementation of high resolution sensors with a very powerful computational capability tailored to computer vision applications.

### 1. INTRODUCTION

Real-time computer vision is a challenging research area for which several custom integrated circuits have been developed in order to achieve higher performance for pattern recognition tasks. It is well-known that major computational resources are needed for low-level image processing like enhancement or edge detection and especially for multiscale edge analysis. Although DSP processing and architecture were integrated to frame grabbers in order to support low-level image processing, the resulting acquisition system must still deal with a large amount of data with little capacity of flexible decision making on what is relevant or not in the scene. In addition, an external video camera must be added to the acquisition system and imposes several functional constraints like frame duration and fixed scanning path. Computational sensing is an emerging research area which combines photo-transduction and signal processing at the sensor level. In a computer vision perspective, this means that analog illuminance signals from a 2D sensor may be used by an analog computing module in order to extract relevant characteristics from the scene. A major consequence of this approach is a significant reduction of data transfer between the sensing unit and the recognition processes.

VLSI technology provides opportunities for the design of a variety of image sensors. An intuitive design strategy refers to retina-like architectures with complex photo-sensitive elements [7] and emphasis on the communication between neighbors [3] [4], but it usually defines sensors with poor spatial resolution. The parallel access of row data at one end of the sensor [2] or an on-chip digital sequential processor [1] have been previously studied. Although these approaches, based on digital theory, are more compact designs than the conventional frame grabber approach, they still offer similar computational power.

A common goal to computational sensing approaches is to

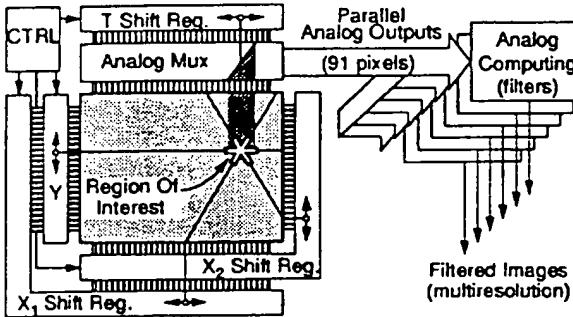
integrate photosensitive elements and analog processing on CMOS technology [8] [11] due to its good yield and spatial regularity. Good 2D image sensor must provide a minimum spatial resolution (typically 200 to 400 pixels per line) when computer vision is targeted as the application. This implies a basic trade-off between pixel complexity (size) and the spatial resolution that is allowed by a given technology for maximum die size. In this paper, an hexagonal CMOS sensor is described with its multi-port access architecture. This allows parallel analog extraction of illuminance data which may be processed externally by a satellite analog processing module. With this architecture, it is possible to perform multiresolution edge extraction using several external integrated filters in parallel without any negative effect on the overall resolution of the sensor. This solution requires different IC technologies on separate dies which makes it a typical candidate for a multi-module chip assembly.

The concept of parallel analog extraction using an hexagonal Multi-port Access photo-Receptor (MAR) sensor is presented in Section 2, including the pixel architecture and sensor operating mode. The parallel analog spatial filtering capability of the MAR system is presented in Section 3 with a typical application for multiresolution edge extraction using custom resistor network IC. The paper concludes in Section 4 with a presentation of parameters obtained from the analog computing module and typical images from a 256 x 256 prototype of the MAR sensor.

### 2. THE MULTI-PORT ACCESS PHOTO-RECEPTOR

A multi-port addressing strategy was chosen for the sensor in order to access, in parallel, a large number of pixels within the sensor but keeping the pixel size as small as possible. The analog processing is transferred to an external custom IC. An hexagonal grid has been selected for the MAR sensor for two main reasons. Firstly, it is relatively easy to extract analog data by a set of parallel busses. The second reason is related to the distance between a given Pixel Of Interest (POI) and its nearest neighbors which is the same along any of the six main directions of the hexagonal tessellation, a condition which considerably facilitates the implementation of circularly symmetric kernels. Figure 2 shows the schematic of each pixel which includes six transistors and one photo-diode. The single current  $I_S$ , generated by the integration of photo-current  $I_F$ , is retrieved through a set of three N-transistors ( $M_Y$ ,  $M_{S1}$  and  $M_{S2}$ ) with individual selection lines. This is similar to a multi-port memory access with individual data busses ( $D_Y$ ,  $D_{S1}$  and  $D_{S2}$  respectively). Each set of selection busses ( $Y$ ,  $X_1$  and  $X_2$ ) is activated by an individual bidirectional shift register. Each signal is routed out via one of these data busses, according to the status of the selection lines. The dark area on top of the convolution kernel on Figure 1 represents the extracted analog data flow until it reaches the parallel analog multiplexor. Pointer  $T$ , which tracks

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**Figure 1** General architecture of the MAR sensor and its associate external multiresolution analog filtering unit. A typical addressing of a pixel of interest is shown on the sensor. The white star represents the convolution kernel which extract illuminance information for 91 pixels.

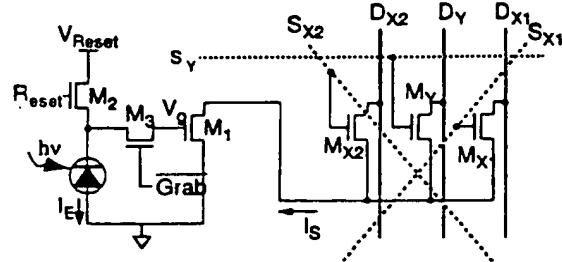
the location of the POI, controls a set of transmission gates that puts each analog signal on the proper output channel.

This topology allows for simultaneous access to the illuminance data of the selected pixel (intersection of the three active selection lines) together with the illuminance of all neighbors located on the three axes of symmetry of the sensor array (corners of the concentric hexagon). It yields a natural compatibility with circularly symmetric operators since all pixels located at the corner of a given hexagon have identical radial distance from the POI. A particularity of the MAR sensor is that the POI may be moved along any of the axes of the underlying hexagonal structure which allows the sensor controller a variety of scanning strategies [10].

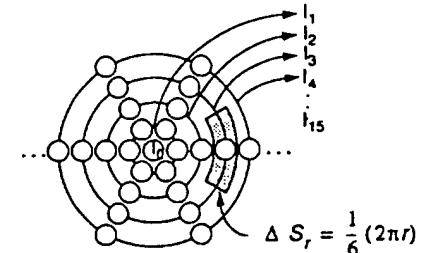
Since each pixel may be accessed several times during a scan period, the read-out must be non-destructive as shown in Figure 2. The circuit of Figure 2 is based on a photo-current  $I_E$  generated by a photo-diode which drives the gate capacitance of transistor  $M_1$  over an adjustable integration interval. The integration process is initialized ( $R_{reset} = 1$  and  $G_{Grab} = 1$ ) by placing a positive voltage ( $V_{Reset} - V_{SN}$ ) through  $M_2$  and  $M_3$  on the gate of  $M_1$ . Transistor  $M_3$  is disabled to stop the integration process during the scanning of the sensor in order to allow uniform integration time throughout the sensor.

### 3. MULTIRESOLUTION CONVOLUTION MODULE

The most interesting property of the proposed architecture is that it allows parallel analog filtering for edge detection at multiple



**Figure 2** The schematic view of the MAR pixel. The right-hand part refers to the multi-port addressing architecture while the left-hand side shows the non-destructive buffering of the analog illuminance data.



**Figure 3** The information from each set of six pixels which are located at the same radial distance from the POI is routed out from the sensor on individual data buses in order to apply circularly symmetric filters.

scales. As previously discussed, the hexagonal tessellation is naturally compatible with circularly symmetrical operators. The Laplacian Of Gaussian (LOG) operator has been identified by Mart et al. [5] [6] as a most natural isotropic edge detector. Unfortunately, their computational cost on sequential computers is quite high. On the MAR architecture, the computation of 10 or 20 simultaneous filtered images is straightforward. It is the most relevant property of the MAR architecture, especially when scale-space integration is planned as an edge reinforcement procedure.

Figure 3 gives an overall view of the star-shaped convolution kernel of the MAR sensor which has a maximum radius of 16 pixels from the POI ( $I_0$ ). Each extracted current  $I_r$  is put on an individual analog output channel, where  $r$  defines the radial distance of the pixel from the POI. Since each analog signal is retrieved via an individual bus, it is not desirable to access all the 91 pixels as individual sensor outputs. Rather, each set of six pixels with equal radius are grouped and dedicated for circularly symmetric operators. The discrete spatial convolution of a given image  $I$  with an operator  $H$  is expressed for the general case as:

$$W[x, y] = \sum_{i=-x}^x \sum_{j=-y}^y H[i, j] I[x - i, y - j] \Delta S \quad (1)$$

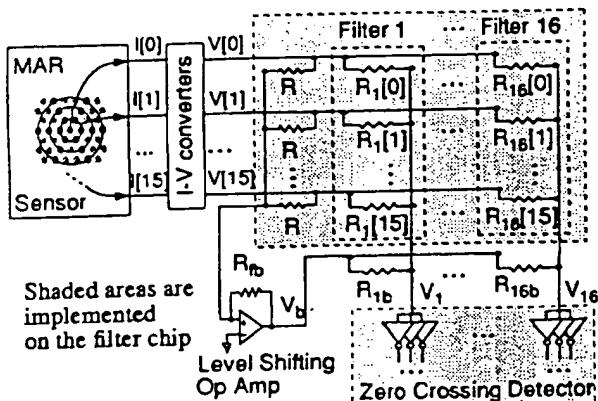
with  $\Delta S$ , the effective area of the sampled pixel (usually a constant and equal to 1). For the particular case of the MAR sensor, where a sub-sampling of the image is made by the convolution kernel, we need to compute the effective area of each selected pixel before applying any weight  $H[i, j]$ . This area is shown in Figure 3 (dark area surrounding a pixel) and has a value of one sixth of the effective ring ( $\Delta S_r = \pi r / 3$ ). The effective size of the center pixel  $I_0$  is the area of a small disk with radius of  $1/2$  ( $\Delta S_0 = \pi / 4$ ). Equation (1) may be corrected for the particular case of the MAR sensor with a circularly symmetric operator  $F_\sigma(r)$ :

$$W_\sigma[r] = \frac{\pi}{3} \left[ \frac{3}{4} F_\sigma[0] I_0 + \sum_{r=1}^{15} r F_\sigma[r] I_r \right] \quad (2)$$

In equation (2), the value of  $F_\sigma[r]$  corresponds to the sampled value of the continuous function  $F_\sigma(r)$  for  $r$  ranging from 0 to 15 pixels. For LOG filters,  $F$  is a function of parameters  $\sigma$  and  $r$  and is given by:

$$F_\sigma[r] = \nabla^2 G_\sigma[r] = \frac{-1}{2\pi\sigma^4} \left( 2 - \frac{r^2}{\sigma^2} \right) e^{-\left(\frac{r^2}{2\sigma^2}\right)} \quad (3)$$

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**Figure 4** Parallel analog filtering module. Each output of the sensor is converted to a voltage signal and processed by a set of resistive networks which implement  $N$  different filters.

One of the most important property of  $F_\sigma[r]$  is its first moment (mean) zero. This can be written as:

$$\sum_{r=0}^{15} F_\sigma[r] p[r] = 0. \quad (4)$$

where  $p[r]$  is the probability density function of  $F_\sigma[r]$  and is defined as  $p[r]=1/9$  for  $r=0$  and  $p[r]=6/9$  for  $r=1, \dots, 15$ . In order to keep this property, the sampled function  $F_\sigma[r]$  is thus modified with a correcting function  $C_\sigma[r]$  after the sampling process so its first moment remains zero.

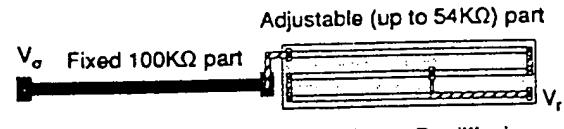
For multiresolution LOG filtering, we synthesize several filters computed by (3) for different values of  $\sigma$ . As shown in Figure 4, each filter is implemented by a simple resistive network connected as an analog adder. The resistor values  $R_\sigma[r]$  are chosen such that their value is proportional to  $1/(rF_\sigma[r])$ . The left-hand part of Figure 4 holds the signal conditioning module as a current-voltage converter. Each filter output  $V_\sigma$  is routed to a zero-crossing detector which transforms the corresponding analog output into a two-bit digital signal: (i) the sign of the analog signal and (ii) the thresholded value of its amplitude. This set of binary values ( $2N$  bits) are stored in an image memory and is later used by the digital controller. Details on the implementation of the zero-crossing and edge tracking algorithms are available in [10].

### 3.1. The LOG Filter as a Resistive Network

In equation (2) the  $F_\sigma[r]$  function yields negative values. This is undesirable since resistor values must be positive. Hence, we compute a different function  $K_\sigma[r] = \gamma_\sigma F_\sigma[r] + Km_\sigma$  which shifts and rescales  $F_\sigma[r]$  to more convenient (positive) values. The operational amplifier (see Figure 4) is used to remove the added offset  $Km_\sigma$  after the convolution operation has been performed on the illuminance signal. In order to compute the scale factor  $\gamma_\sigma$  and the offset  $Km_\sigma$ , we must consider the layout level of the NTE CMOS3DLM process.

The 272 resistors of the filter chip were built using the same custom template (see Figure 5). The template has a ratio close to 16:1. This enables the making of almost squared macro-cells, optimizing the use of the silicon area.

The lowest value for any resistor can be determined by observing that one output of the I-V converter has to drive 16 parallel



**Figure 5** The template resistor. The P-well has a high resistivity of  $4K\Omega$  per square and the device well has a low resistivity of  $300\Omega$  per square.

resistors. Since the minimum load each output of the converter can drive is about  $5K\Omega$ , the minimum value for any resistor is  $80K\Omega$ . We chose  $R_{min} = 100K\Omega$  to maintain a security margin. The maximum value for a resistor is determined by geometrical considerations to optimize the silicon area as explained above. The maximum value is  $R_{max} = 154K\Omega$ . We can now compute  $Km_\sigma$  and  $\gamma_\sigma$ . Let

$$Km_\sigma + \gamma_\sigma F_{\sigma min} = K_{\sigma min} = \frac{1}{R_{\sigma max}}, \text{ and} \quad (5)$$

$$Km_\sigma + \gamma_\sigma F_{\sigma max} = K_{\sigma max} = \frac{1}{R_{\sigma min}}, \quad (6)$$

where  $F_{\sigma max} = \text{Max}(F_\sigma[r])$  and  $F_{\sigma min} = \text{Min}(F_\sigma[r])$ . The solution of equations (5) and (6) is straightforward. The resistors values of the filters are:

$$(R_\sigma[r])^{-1} = K_\sigma[r] = \gamma_\sigma F_\sigma[r] + Km_\sigma. \quad (7)$$

The  $R_\sigma$  values are used along with the operational amplifier to remove the offset. The equation of the circuit is:

$$V_\sigma = \frac{\sum_{r=0}^{15} \frac{V[r]}{R_\sigma[r]} p[r] - \frac{R_{fb}}{RR_{ob}} \sum_{r=0}^{15} V[r] p[r]}{\sum_{r=0}^{15} \frac{1}{R_\sigma[r]} p[r] + \frac{1}{R_{ob}}} \quad (8)$$

where  $p[r]$  is the density function of the variables  $R$  and  $R_\sigma[r]$ . For the iso-illuminance case, that is when all the  $V[r]$ 's are equal, the property stated in equation (4) implies that  $V_\sigma = 0$  volt. We can then solve (8) to obtain

$$R_{ob} = \left[ \sum_{r=0}^{15} \frac{p[r]}{R_\sigma[r]} \right]^{-1}. \quad (9)$$

All the resistor values are set for every filter.

### 3.2. The Zero-Crossing Detector

The analog outputs  $V_\sigma$  of the filters are routed to a zero-crossing detector. The analog signal is transformed into a 2-bit digital value. The shape of  $V_\sigma$  is shown on Figure 6(a). To detect the sign of  $V_\sigma$ , a simple CMOS inverter with a switching level of 0 volt is required. To detect the thresholded value of the amplitude ( $t_{V_\sigma}$ ), two programmable switching level inverters, one inverter and one nand gate are required as shown on Figure 6(b). This is done by splitting and lowering the ground levels of the inverters. The actual values are also shown. The binary values are stored in an image memory.

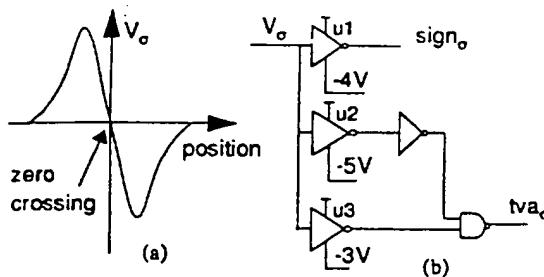


Figure 6 (a) Cross-section of a convolved image. (b) The zero-crossing detector. The switching level of the inverters are 0V, -1V and +1V for U1, U2 and U3.

#### 4. RESULTS

Preliminary experiments of the zero-crossing detector show that its maximal frequency of operation is around 40MHz. The resistors of the networks were measured experimentally and equations (7) back to (4) were recomputed with measured values. Table 1 shows the normalized moments of measured  $F_o[r]$  compared with theoretical values. This is a quantification of the rejection of uniform illuminance. A 256x256 pixels version of the MAR sensor

Table 1: Normalized moments of some measured  $F_o[r]$ .

Filter ( $\sigma$ )	Mean value		Variance values	
	Theory	Measured	Theory	Measured
0 (0.5)	0	-1.41E-03	0.192	0.198
1 (0.7)	0	6.06E-03	12.4E-03	13.0E-03
5 (1.3)	$10^{-19}$	1.36E-03	439E-06	469E-06
9 (2.4)	$10^{-19}$	269E-06	17.0E-06	17.0E-06
15 (6.9)	$10^{-20}$	40.2E-06	142E-09	125E-09

is currently installed in a custom camera case. This version implements sixteen different filters. Several image acquisitions have been performed on different scenes as a proof-of-concept. Typical results are shown in Figure 7 along with the resulting edge data. The upper left part is the illuminance image in an hexagonal sampling format and the upper right part is the resulting edge map following scale-space integration [10] of the sixteen primary multiresolution edge images. Two of the sixteen primary edge maps are shown on the bottom for two different spatial resolutions.

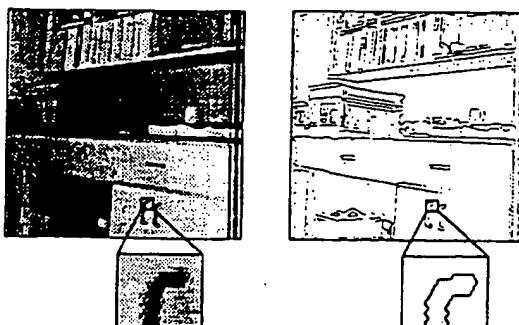


Figure 7 Results from a typical scene for a 256 x 256 hexagonal MAR sensor.

(Note that black dots in the illuminance image is caused by noise on power lines due to the temporary installation of the Analog to Digital converter and are not found in edges maps). Small zoom boxes are used in order to show the hexagonal tessellation of the illuminance image and for the orientation of primary edge segments which are oriented in one of the third main direction of the hexagonal structure (at 60 degrees). The high pass filter ( $\sigma=0.8$ ) extracts accurate but noisy edges, while the low pass one ( $\sigma=2.4$ ) finds only the smooth variations of illuminance. The integration of these informations is made by detecting relevant edges with the low pass filters and localizing them with high accuracy using high pass filters outputs. All of these edge maps are generated simultaneously by the analog computing module in a single frame period.

#### 5. CONCLUSION

An hexagonal multi-module image sensor has been presented and is designed to link acquisition with tightly integrated satellite processing. The feasibility of a sensor with a resolution up to 500 x 500 pixels is an important consequence of this concept. The analog processing architecture was also detailed. A digital controller and several co-processing units are under development. This entire system will define a smart image acquisition device which could be used for general computer vision application and particularly for pattern recognition in robot vision.

#### 6. ACKNOWLEDGEMENTS

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